



Title of Change:	AR0144CS Outgoing Defect Specification Mono Update.	
Effective date:	15 August 2018	
Contact information:	Contact your local ON Semiconductor Sales Office or < sonya.yip@onsemi.com >	
Type of notification:	This Product Bulletin is for notification purposes only. ON Semiconductor will proceed with implementation of this change upon publication of this Product Bulletin.	
Change Category:	<input type="checkbox"/> Wafer Fab <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input checked="" type="checkbox"/> Other <u>Documentation</u>	
Change Sub-Category(s):	<input type="checkbox"/> Manufacturing Site Addition <input type="checkbox"/> Material Change <input checked="" type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Manufacturing Site Transfer <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Other: _____	
Sites Affected:	ON Semiconductor Sites: None	External Foundry/Subcon Sites: None
Description and Purpose: <p>AR0144CS Outgoing Defect Specification was updated to correct an error. These changes do not affect form, fit, or function of the product.</p> <p>AR0144CS Outgoing Defect Specification Changes</p> <p>1. In Conditions for Image Test B, changed "Sensor analog gain is 1.77x, digital gain is 1x" to "Sensor analog gain is 1.7x, digital gain is 1x"</p> <p>Old Section:</p> <p><i>Conditions for Image Test B</i> The following test conditions are used for "Definition 3: Very Bright Pixel Defect", "Definition 4: Bright Pixel Defect", "Definition 5: Very Dark Pixel Defect", and "Definition 6: Dark Pixel Defect":</p> <ul style="list-style-type: none"> Full resolution images (four frames) are captured using a 1 ms integration time with a midlevel scene illumination such that sensor output is about 2800 LSBs. Frames are averaged for analysis Sensor analog gain is 1.77x, digital gain is 1x <p>New Section:</p> <p><i>Conditions for Image Test B</i> The following test conditions are used for "Definition 3: Very Bright Pixel Defect", "Definition 4: Bright Pixel Defect", "Definition 5: Very Dark Pixel Defect", and "Definition 6: Dark Pixel Defect":</p> <ul style="list-style-type: none"> Full resolution images (four frames) are captured using a 1 ms integration time with a midlevel scene illumination such that sensor output is about 2800 LSBs. Frames are averaged for analysis Sensor analog gain is 1.7x, digital gain is 1x 		



List of Affected Parts:

AR0144CSSC00SUKA0-CPBR
AR0144CSSC00SUKA0-CRBR
AR0144CSSM00SUKA0-CPBR
AR0144CSSM00SUKA0-CRBR
AR0144CSC20SUKA0-CPBR
AR0144CSC20SUKA0-CRBR
AR0144CSSM20SUKA0-CPBR
AR0144CSSM20SUKA0-CRBR
AR0144CSC00SUD20
AR0144CSC20SUD20
AR0144CSSM00SUD20
AR0144CSSM20SUD20
AR0144CSSM28SUD20